Search Notes

Application/Control No.	Applicant(s)/Patent un Reexamination	Applicant(s)/Patent under Reexamination	
10/048,023	IWASAKI, YASUKAZI	J	
Examiner	Art Unit		
Alexis Wachtel	1764		

	SEAR	CHED	
Class	Subclass	Date	Examiner
·			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		· · · · · · · · · · · · · · · · · · ·		

SEAR (INCLUDING SI	CH NOTES		·)
		DATE	EXMR
inventor search	1	2/26/2005	